TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (π-MOSV)

# 2SK2602

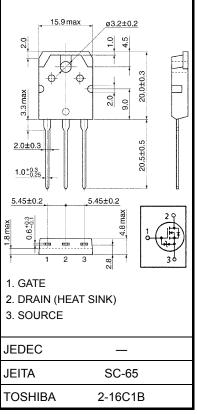
### **Switching Regulator Applications**

Unit: mm

 $\begin{array}{ll} \bullet & Low \ drain-source \ ON \ resistance & : R_{DS} \ (on) = 0.9 \ \Omega \ (typ.) \\ \bullet & High \ forward \ transfer \ admittance & : |Y_{fs}| = 5.5 \ S \ (typ.) \\ \bullet & Low \ leakage \ current & : I_{DSS} = 100 \ \mu A \ (max) \ (V_{DS} = 600 \ V) \\ \bullet & Enhancement \ mode & : V_{th} = 2.0 \sim 4.0 \ V \ (V_{DS} = 10 \ V, \ I_{D} = 1 \ mA) \\ \end{array}$ 

### **Absolute Maximum Ratings (Ta = 25°C)**

Characteris	stics	Symbol	Rating	Unit	
Drain-source voltage		$V_{DSS}$	600	V	
Drain-gate voltage (Ro	<sub>SS</sub> = 20 kΩ)	$V_{DGR}$	600	V	
Gate-source voltage		V <sub>GSS</sub>	±30	V	
Drain current	DC (Note 1)	ID	6	Α	
	Pulse (Note 1)	I <sub>DP</sub>	24	Α	
Drain power dissipation	r (Tc = 25°C)	P <sub>D</sub>	125	W	
Single pulse avalanche	e energy (Note 2)	E <sub>AS</sub>	345	mJ	
Avalanche current		I <sub>AR</sub>	6	Α	
Repetitive avalanche e	nergy (Note 3)	E <sub>AR</sub>	12.5	mJ	
Channel temperature		T <sub>ch</sub>	150	°C	
Storage temperature ra	ange	T <sub>stg</sub>	-55~150	°C	



Weight: 4.6 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

#### **Thermal Characteristics**

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R <sub>th (ch-c)</sub>	1.0	°C/W
Thermal resistance, channel to ambient	R <sub>th (ch-a)</sub>	50	°C/W

Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2:  $V_{DD}$  = 90 V,  $T_{ch}$  = 25°C (initial), L = 16.8 mH,  $R_G$  = 25  $\Omega$ ,  $I_{AR}$  = 6 A

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device.

Please handle with caution.



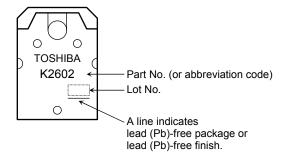
## **Electrical Characteristics (Ta = 25°C)**

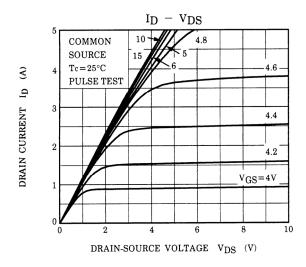
Charac	cteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	ırrent	I <sub>GSS</sub>	V <sub>GS</sub> = ±25 V, V <sub>DS</sub> = 0 V	_	_	±10	μA
Gate-source bre	eakdown voltage	V (BR) GSS	I <sub>G</sub> = ±10 μA, V <sub>DS</sub> = 0 V	±30	_	_	V
Drain cut-off cu	rrent	I <sub>DSS</sub>	V <sub>DS</sub> = 600 V, V <sub>GS</sub> = 0 V	_	_	100	μA
Drain-source br	eakdown voltage	I (BR) DSS	I <sub>D</sub> = 10 mA, V <sub>GS</sub> = 0 V	600	_	_	V
Gate threshold v	/oltage	$V_{th}$	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	2.0	_	4.0	V
Drain-source O	N resistance	R <sub>DS (ON)</sub>	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 3 A,		0.9	1.25	Ω
Forward transfer	r admittance	Y <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 3 A	2.0	5.5	_	S
Input capacitano	e	C <sub>iss</sub>		_	1300	_	
Reverse transfer capacitance		C <sub>rss</sub>	V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 0 V, f = 1 MHz	_	130	_	pF
Output capacitance		Coss		_	400	_	
Switching time	Rise time	t <sub>r</sub>	$V_{GS} = \frac{10V}{0V} \int_{V_{OU}} V_{OU} V_{O$	_	25	_	
	Turn-on time	t <sub>on</sub>		ı	45	_	ns
	Fall time	t <sub>f</sub>			40	_	115
	Turn-off time	t <sub>off</sub>			150	_	
Total gate charge (gate-source plus gate-drain)		Qg			30		
Gate-source charge		Q <sub>gs</sub>	$V_{DD} \approx 400 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 6 \text{ A}$		18	_	nC
Gate-drain ("miller") Charge		Q <sub>gd</sub>			12	_	

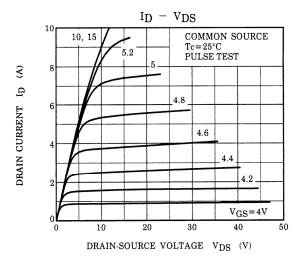
### **Source-Drain Ratings and Characteristics (Ta = 25°C)**

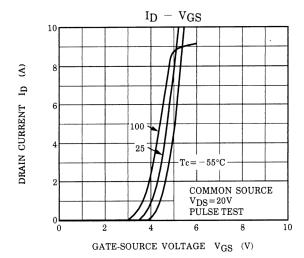
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I <sub>DR</sub>	_	_	_	6	А
Pulse drain reverse current (Note 1)	I <sub>DRP</sub>	-	_	_	24	А
Forward voltage (diode)	V <sub>DSF</sub>	I <sub>DR</sub> = 6 A, V <sub>GS</sub> = 0 V	_	_	-1.7	V
Reverse recovery time	t <sub>rr</sub>	$I_{DR} = 6 \text{ A}, V_{GS} = 0 \text{ V}, dI_{DR} / dt = 100 \text{ A} / \mu \text{s}$	_	1000	_	ns
Reverse recovery charge	Qrr		-	7		μC

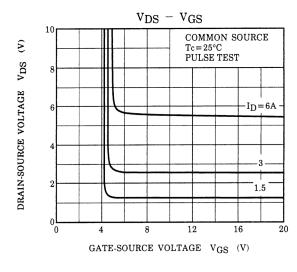
## Marking

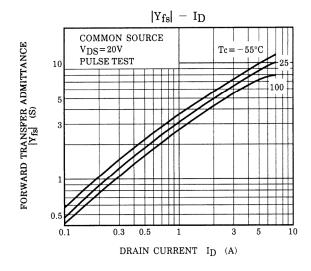


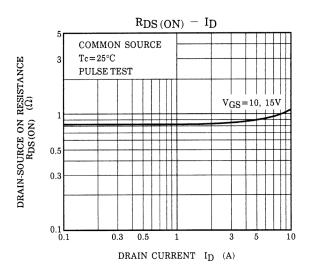




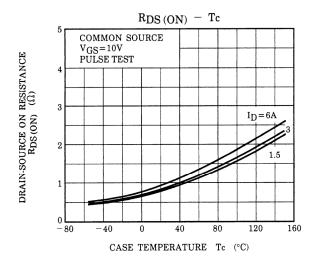


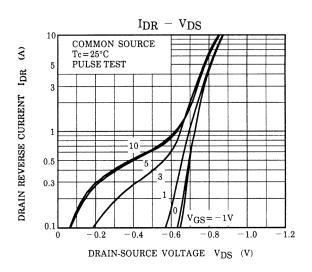


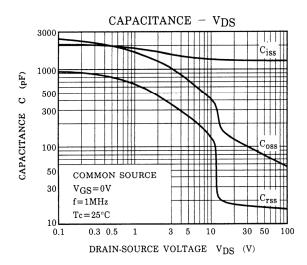


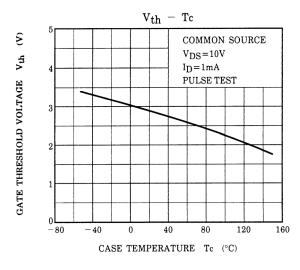


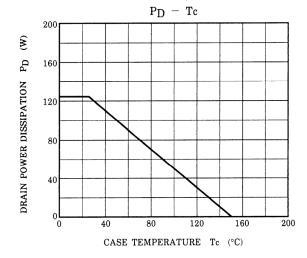
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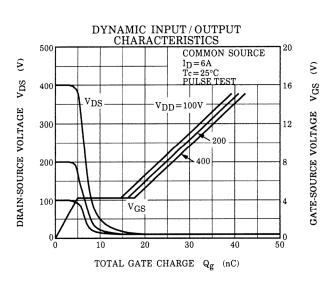


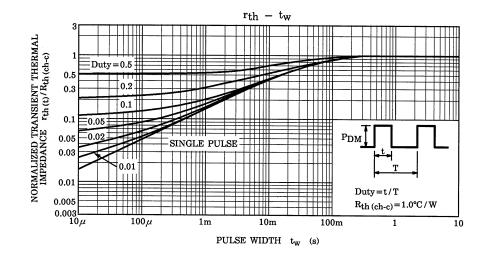


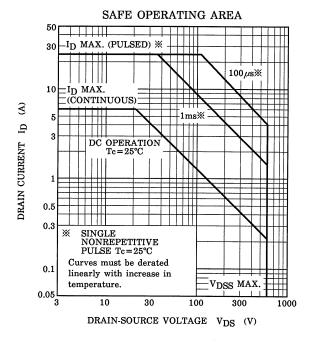


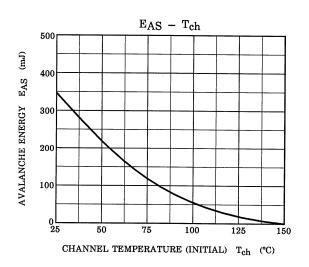


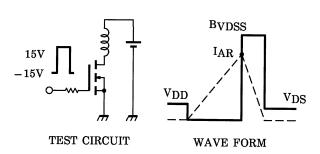












$$\begin{aligned} &R_G = 25~\Omega \\ &V_{DD} = 90~V,~L = 16.8~mH \end{aligned} \quad E_{AS} = \frac{1}{2} \cdot L \cdot I^2 \cdot \left( \frac{B_{VDSS}}{B_{VDSS} - V_{DD}} \right)$$

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